

SIMULATED 2,4-D DRIFT ON ROUNDUP-READY SOYBEAN. Andrew P. Robinson, William G. Johnson, Jerry W. Keaton and David M. Simpson, Graduate Research Assistant and Professor, Department of Botany and Plant Pathology, Purdue University, 915 W. State St., West Lafayette, IN 47907, Dow AgroSciences, 9330 Zionsville Rd., Indianapolis, IN 46268.

New trait technologies incorporating 2,4-D tolerance in soybean will increase the use of 2,4-D causing a greater potential for drift. Our objective was to quantify crop injury and yield loss from 2,4-D drift on glyphosate-tolerant soybean. Ten rates (0, 0.112, 1.12, 11.2, 35, 70, 140, 280, 560 and 2240 g ae ha⁻¹) were applied at three timings (V2, V5 and R2) on Becks brand 342NRR soybean planted at Lafayette and Fowler, IN. Across application timings, crop injury was most to least injurious at 14>21>28>42 days after treatment. Yield components will be reported.